

# The varied nature and roles of nanoscale surface defects in perovskite thin films

Sofiia Kosar<sup>1</sup>, Andrew J. Winchester<sup>1</sup>, Tiarnan A. S. Doherty<sup>2</sup>, Stuart Macpherson<sup>2</sup>, Christopher E. Petoukhoff<sup>1</sup>, Kyle Frohna<sup>2</sup>, Miguel Anaya<sup>2</sup>, Nicholas S. Chan<sup>1</sup>, Julien Madéo<sup>1</sup>, Michael K. L. Man<sup>1</sup>, Samuel D. Stranks<sup>2</sup>, Keshav M. Dani<sup>1</sup>

<sup>1</sup>Femtosecond Spectroscopy Unit, Okinawa Institute of Science and Technology Graduate University, 1919-1, Onna, Okinawa, 904-0495, Japan

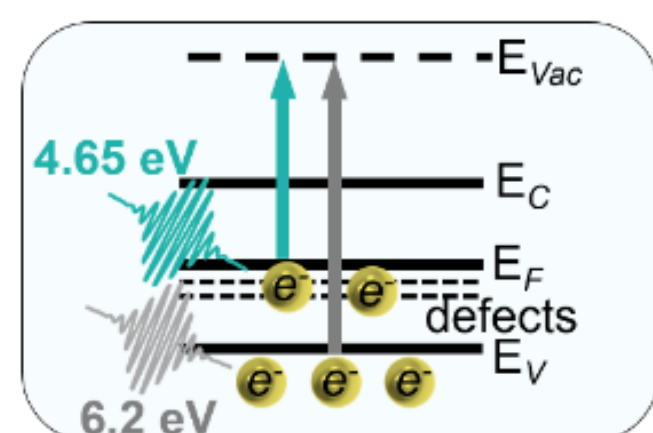
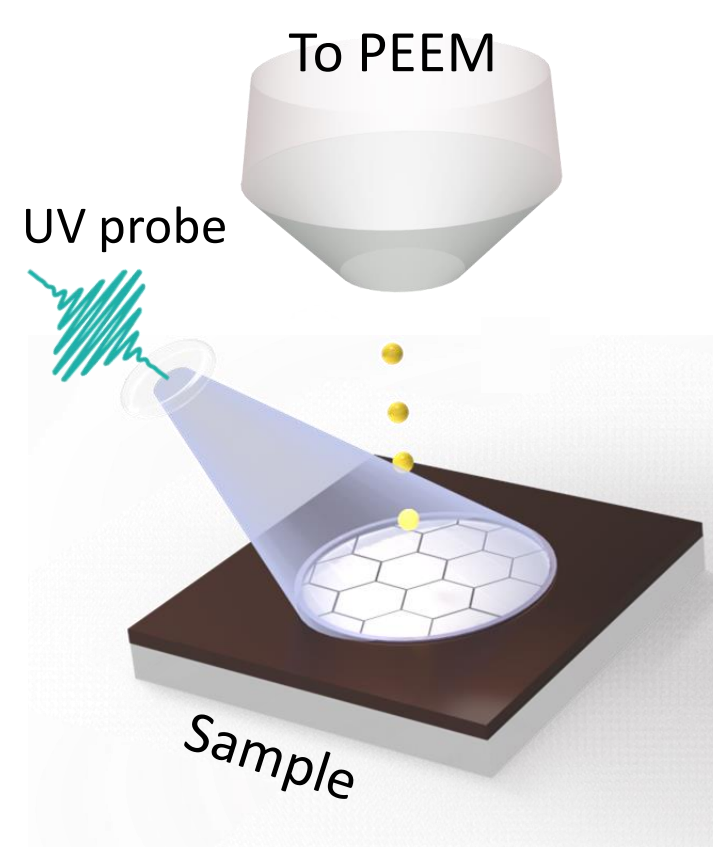
<sup>2</sup>Optoelectronic Materials and Device Spectroscopy Group, Cavendish Laboratory, University of Cambridge, JJ Thomson Avenue, Cambridge, CB3 0HE, UK.

**Abstract:** we identified multiple types of nanoscale defects in hybrid perovskite thin films and found that they play different roles in charge trapping: from highly detrimental to relatively benign.

## 1. What are hybrid halide perovskites?

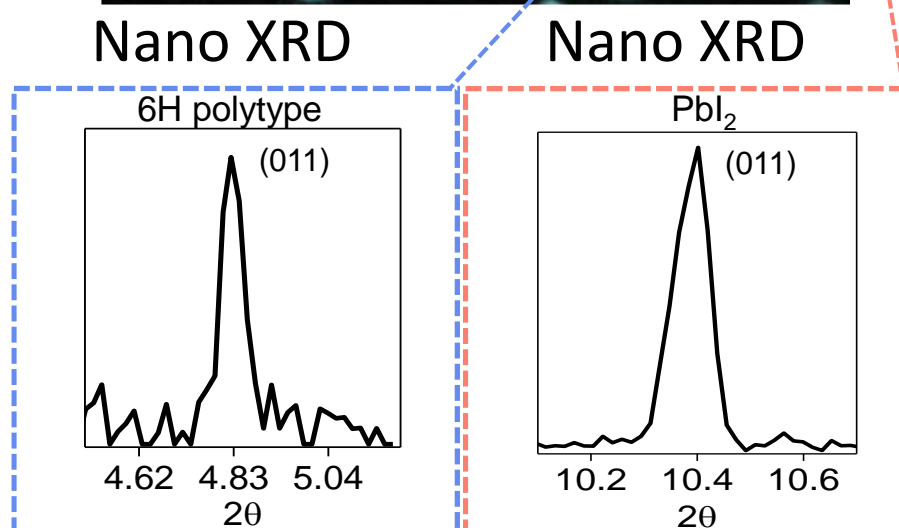
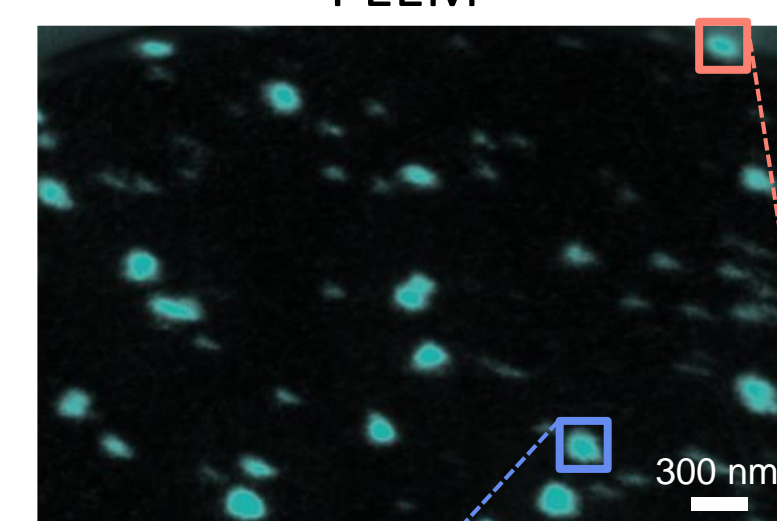
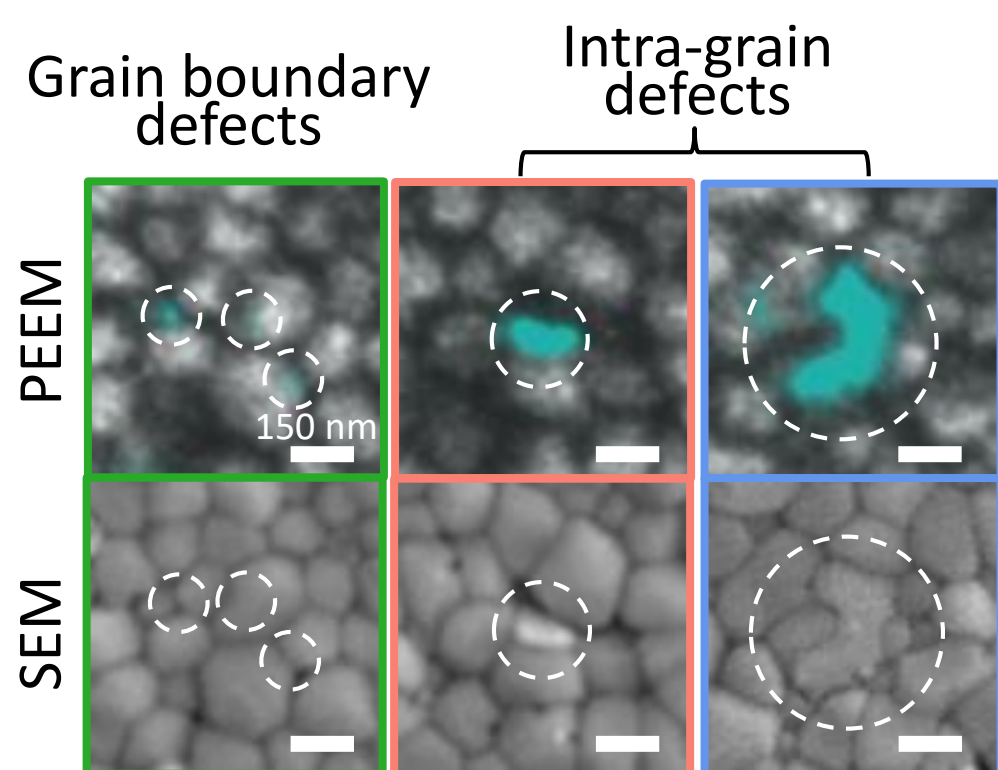
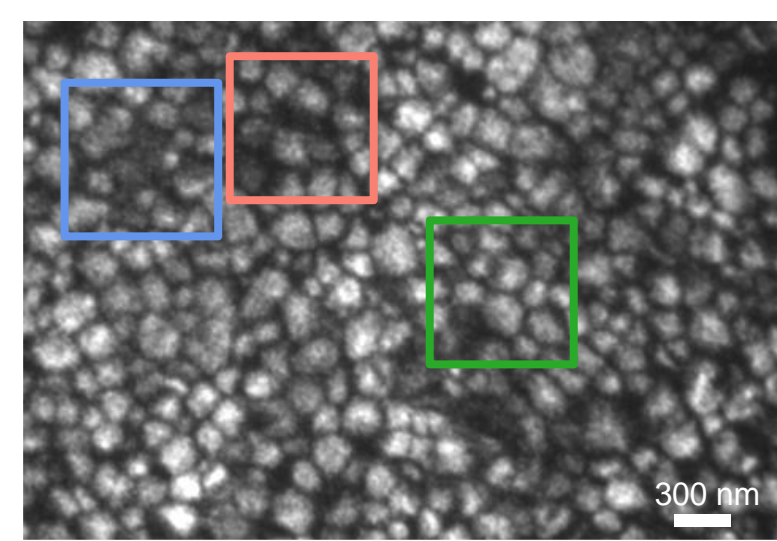
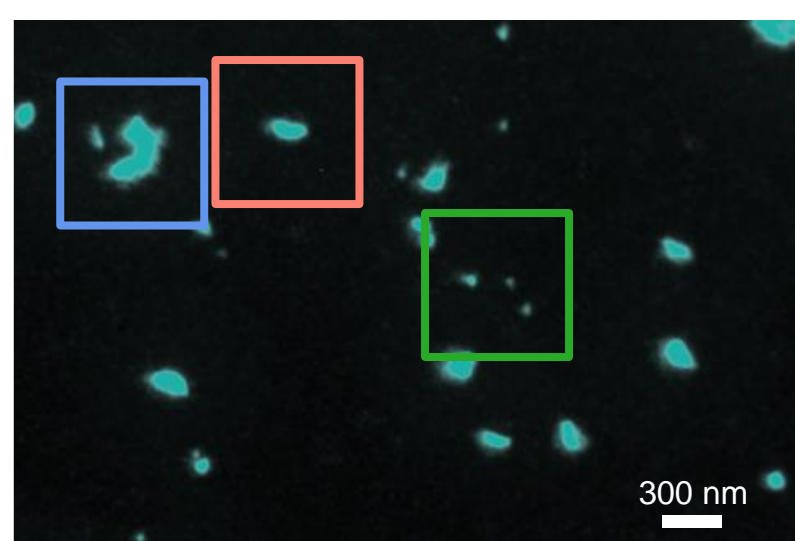
- Semiconducting materials that are used to fabricate state-of-the-art solar cells.
- Efficiency of perovskite solar cells reached 25.7 % in single junction configuration, which is comparable to efficiencies of single crystal silicon solar cells (26.1%) [1].
- Performance of perovskite thin films is impacted by the presence of defects [2].
- Defects in perovskites have been reported to induce non-radiative losses that occur on microscale [3].

## 2. Imaging defects and grains in hybrid perovskites



- With 4.65 eV probe photons we imaged occupied mid gap (defect) states in perovskite thin films [4].
- With 6.2 eV probe photons, we imaged surface morphology of polycrystalline perovskite films.

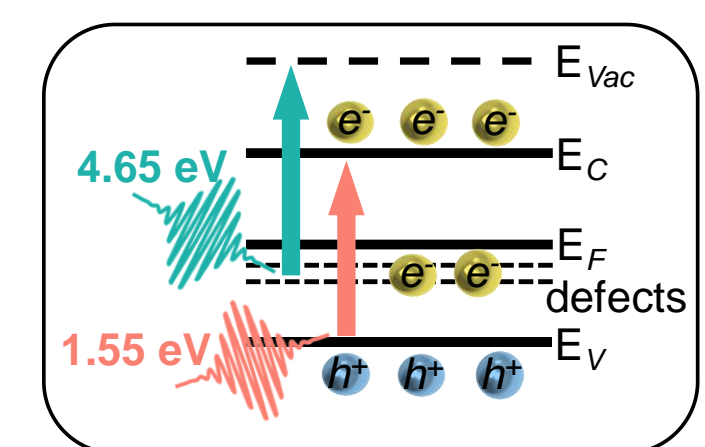
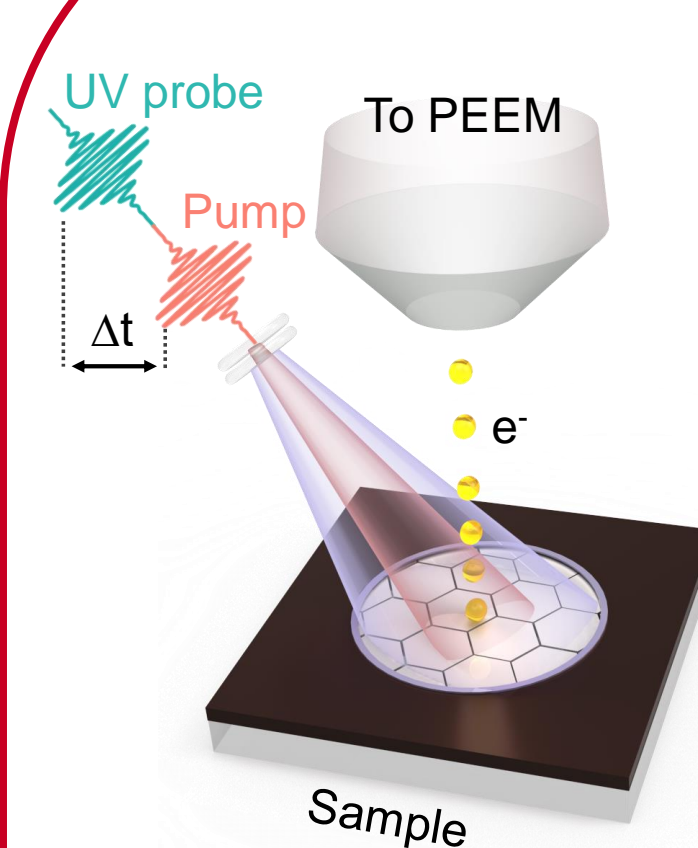
PEEM image of nanoscale defects    PEEM image of surface morphology



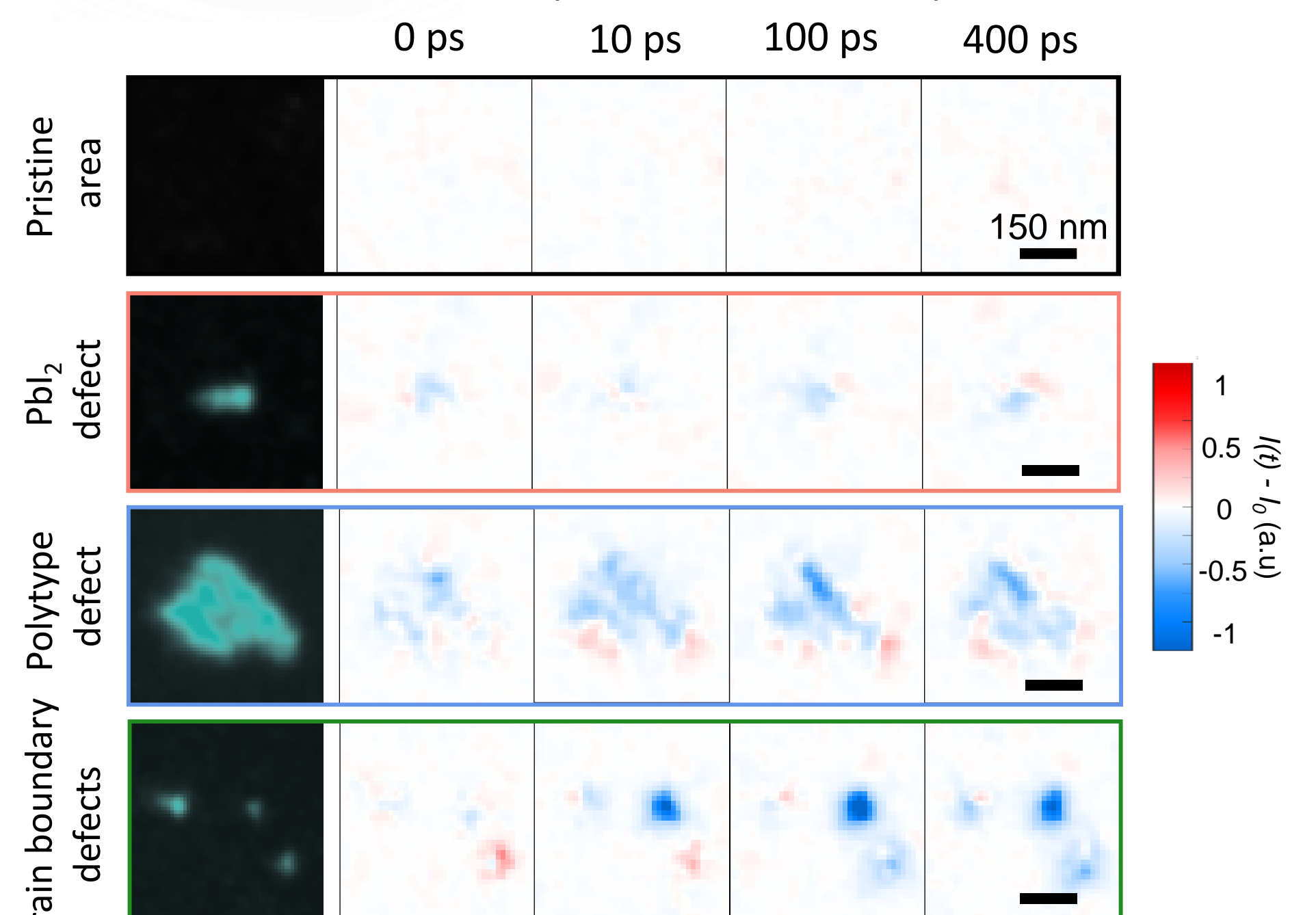
- Nanoscale defects in perovskite were categorized into grain boundary and intra-grain defects.

- Intra-grain defects were associated with Pbl<sub>2</sub> and 6H hexagonal polytype perovskite phases [5].

## 3. Trapping dynamics of different defect types



- With pump photons, we photo-excite electrons from valence band to conduction band of perovskite.
- With UV probe photons, we monitor the response of defects to photo-excitation.



- Reduction in PEEM intensity  $[I(t) - I_0]$  after photo-excitation indicates reduction of population of defect states, or trapping of photo-excited holes.
- Defects associated with Pbl<sub>2</sub> phases, were not observed to participate in trapping of charges from perovskite.
- Defects associated with polytype phase and grain boundary defects, showed hole trapping signal. This hole trapping results in non-radiative recombination and reduces performance of perovskites [5].

## 4. Conclusion

- Cs<sub>0.05</sub>MA<sub>0.17</sub>FA<sub>0.78</sub>(I<sub>0.83</sub>Br<sub>0.17</sub>)<sub>3</sub> perovskite thin films contain multiple types of nanoscale surface defects.
- Intra-grain defects are associated with lead iodide and hexagonal polytype phase impurities.
- Defects associated with hexagonal polytype phase and grain boundary defects, participate in trapping of photo-excited holes.
- Defects related to Pbl<sub>2</sub> were not observed to trap charges when photo-exciting perovskite.
- Defective phase impurities should be eliminated to improve performance of perovskite thin films.